

December 1994 Revised July 1999

74F00

Quad 2-Input NAND Gate

General Description

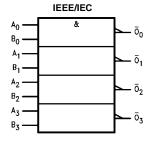
This device contains four independent gates, each of which performs the logic NAND function.

Ordering Code:

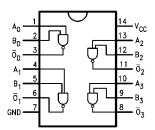
Order Number	Package Number	Package Description					
74F00SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow					
74F00SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide					
74F00PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide					

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}		
Fill Names	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
A _n , B _n	Inputs	1.0/1.0	20 μA/-0.6 mA		
\overline{O}_n	Outputs	50/33.3	−1 mA/20 mA		

Absolute Maximum Ratings(Note 1)

Storage Temperature -65°C to +150°C -55°C to +125°C

Ambient Temperature under Bias Junction Temperature under Bias $-55^{\circ}C$ to $+150^{\circ}C$ V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30~mA to +5.0~mA

Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC}

3-STATE Output -0.5V to +5.5V

Current Applied to Output

twice the rated I_{OL} (mA) in LOW State (Max) ESD Last Passing Voltage (Min) 4000V

Recommended Operating Conditions

Free Air Ambient Temperature 0° C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation

under these conditions is not implied.

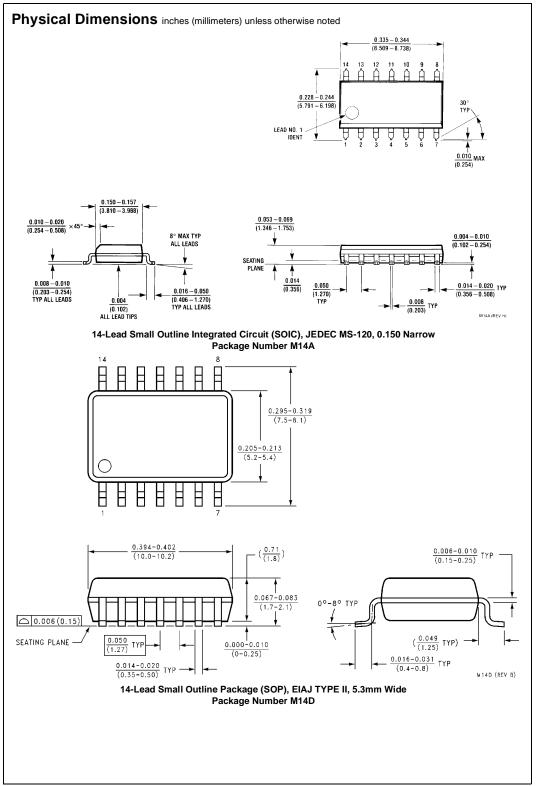
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

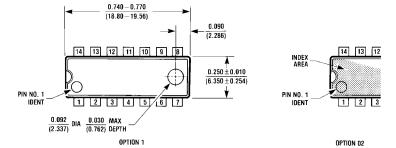
Symbol	l Parameter		Min	Тур	Max	Units	v _{cc}	Conditions	
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	I _{IN} = -18 mA	
V _{OH}	Output HIGH	10% V _{CC}	2.5			V	Min	I _{OH} = -1 mA	
	Voltage	5% V _{CC}	2.7					$I_{OH} = -1 \text{ mA}$	
V _{OL}	Output LOW	10% V _{CC}	10% V _{CC} 0.5		V	Min	I 20 mA		
	Voltage				0.5	V	IVIII	I _{OL} = 20 mA	
I _{IH}	Input HIGH Current				5.0	μА	Max	\/ - 2.7\/	
					5.0			$V_{IN} = 2.7V$	
I _{BVI}	Input HIGH Current Breakdown Test				7.0		Max	V 7.0V	
						μΑ		V _{IN} = 7.0V	
I _{CEX}	Output HIGH				50		Max	V V	
	Leakage Current				50	μΑ	IVIAX	$V_{OUT} = V_{CC}$	
V _{ID}	Input Leakage Test		4.75			V	0.0	$I_{ID} = 1.9 \mu A$	
							0.0	All other pins grounded	
I _{OD}	Output Leakage Circuit Current				3.75	μΑ	0.0	V _{IOD} = 150 mV	
							0.0	All other pins grounded	
I _{IL}	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$	
Ios	Output Short-Circuit Curre	ent	-60		-150	mA	Max	V _{OUT} = 0V	
I _{CCH}	Power Supply Current			1.9	2.8	mA	Max	V _O = HIGH	
I _{CCL}	Power Supply Current			6.8	10.2	mA	Max	$V_O = LOW$	

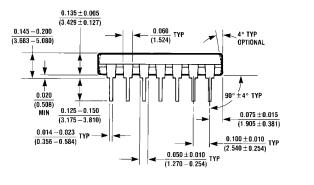
AC Electrical Characteristics

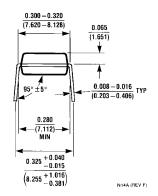
	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$			$T_{A} = -55 ^{\circ} C \text{ to } +125 ^{\circ} C$ $V_{CC} = +5.0 V$ $C_{L} = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		Units
Symbol									
		Min	Тур	Max	Min	Max	Min	Max	İ
t _{PLH}	Propagation Delay	2.4	3.7	5.0	2.0	7.0	2.4	6.0	no
t _{PHL}	A_n , B_n to \overline{O}_n	1.5	3.2	4.3	1.5	6.5	1.5	5.3	ns



Physical Dimensions inches (millimeters) unless otherwise noted (Continued)







14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N14A

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